High-Frequency Probe

HFS-810 201 051 A 5306

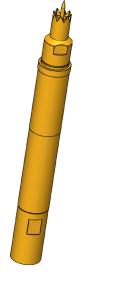
Item HFS-810-0014





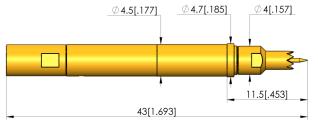
- Long standard series
- Up to 2 GHz
- Cable interface MCX
- Plug-in version
- Receptacles: KS-810, KS-810 R, KS-810 F

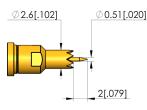












General data

Product group: HFS radio-frequency test probes HFS-810 Series: Sub-series: HFS-810 Grid: 5.8 mm [228 mil] DUT / contact: PCB coax, closed Installation type: Plug-in Floating mount: No Non-rotating: Yes Continuous plunger: Yes Interface of compatible assembly: MCX 50 Ohm Compatible assembly interface gender: M signal conductor male / pin KS sub-series: KS-810, press-in version Min. temperature: -40 °C [-40 °F] 80 °C [176 °F] Max. temperature:

Outer conductor data

RoHS-compliant:

Outer conductor tip style:

Outer conductor tip style diameter:

Spring force of entire outer conductor at working stroke:

Outer conductor working stroke:

Outer conductor maximum stroke:

Exchangeable outer conductor:

Outer conductor max. current load capacity:

06 serrated

2.6 mm [.102 in]

4 N [14.3 ozf]

5 mm [.157 in]

KO-810-0156

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Inner conductor data

Inner conductor tip style: 01 30° needle tip, self-cleaning Inner conductor tip style diameter: 0.51 mm [.02 in] Inner conductor tip style material: 2 steel Inner conductor tip style surface: A gold Number of inner conductors: Exchangeable inner conductor: GKS-051-0001 Inner conductor working stroke: 2 mm [.078 in] Spring force of each inner conductor at working stroke: 1.3 N [4.67 ozf] Inner conductor maximum stroke: 3.7 mm [.145 in] Inner conductor max. current load capacity: 2 A

Electrical data

Yes

Frequency range up to: 2 GHz Impedance: 50 Ohm

Mechanical data

Total spring force at working stroke:5.3 N [19 ozf]Total length:43 mm [1.69 in]Barrel diameter:4.5 mm [.177 in]Installation height without receptacle:11.5 mm [.452 in]

Learn more about **Radio-frequency test probes**



